

Ex Loss sensitive to changes in input signal

a) Gain is less in IFET amphifiers. Hence gain

B.W product is less

10) It is of two types

Namely n-channel &

P-channel FETS. I as

8) Highly sensitive to charges in ilp signal.

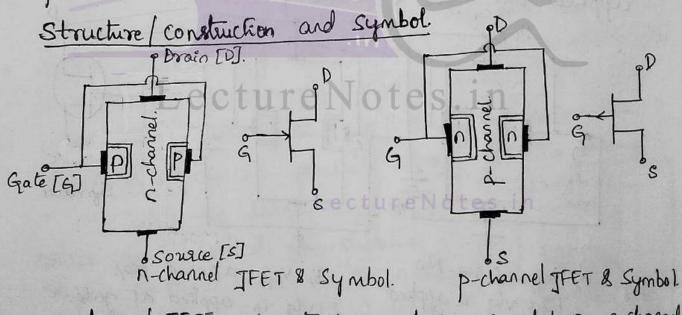
9) Gain is large in BJT

Amplefiers. Hence gain
Bandwidth product is large.

10) BJT is also of two types upon transistor and pup transistors.

The JFET

The JFET Ejunckon field effect transistor is a type of FET that operates with a reverse biased projunction to control current in a channel. Depending on the structure JFETs are classified into n-channel and P-channel. JFET.



n-channel JFET: The structure and the symbol of n-channel JFET is as shown in fig above. The major part of the structure is the n-type material which forms the channel blue the embedded layers of p-type material. It has fore ohmic contacts. The wire leads are connected

to each end of the n-channel. The Drain is the upper end and the source is at the lower end. The two p-type regions are diffused into n-type material to form a n-channel. The p-type regions are connected as gate terminal. In the absence of any applied potential the JFET has two p-n junckons runder no bias conditions.

P-channel IFET: In this the major part is p-type material. The two n-type material is diffused into the P-type material to form a p-channel. The two n-type material are connected to gether to form a gate terminal. The structure and the symbol is as shown in fig.

operation of n-channel JFET

Let us consider n-channel JFET biased with VDS [ vig applied blw drain & source] and vas [ vig applied blw drain & source] and vas [ vig applied blw gate & source.

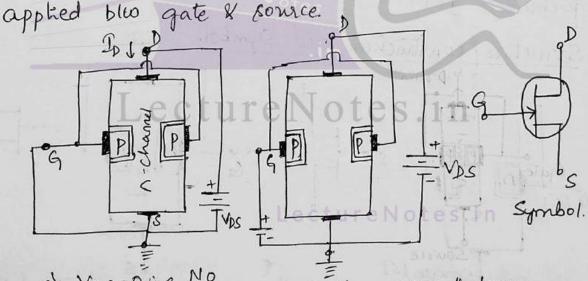


fig. a) Vgs=0 i e No bias vlg is applied vlg is applied at gate.

Capeix when  $V_{GS} = 0$  and  $V_{DS} = +ve$  potential.

when popitive  $v_{GS} = 0$  applied at the drain,  $E_{CONNecking}$  gate terminal to ground i.e.  $V_{GS} = 0$ 

constantly kept in leverse biased conditions. Since the por junction is reverse biased there will be very small amount of current of eventually it is zero. i.e Ig=0. Because of the VDS applied blue the drain & source, which attaracts the electrons from the n-material which leads to flow of current from Drain to source as shown in figure.

Due to connected vig, the majority carriers i e elections begin to flow from some to dearn reducing the depletion region and interases the channel width this steam of elections makes the dearn werent. In.

Since gate is heavily doped and the channel is lightly doped, the width of the depletion region will spread in the Channel. Since n-material is resiptive, the drain current causes a vig across the channel. this vig drain current causes a vig across the channel. the drap reverse biases the p-n junction and causes the depletion regions to peretrate slowly into the channel.

when the large negative gate source vig is applied the depletion region penetrates more into the n-channel. The depletion region width is more the depletion region width is more at deain side compared to source side in tigue. As we go on inversing negative vig across gate source inversing negative vig across gate source

the depletion regions almost toucheach other Scanned by CamScanner

which makes death werent to reduce.

Construction and working of p-channel JFET.

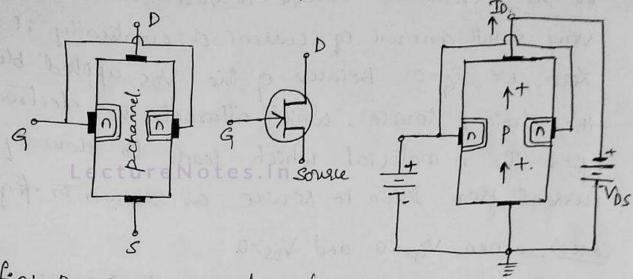


fig: Biasing & p-channel TFET.

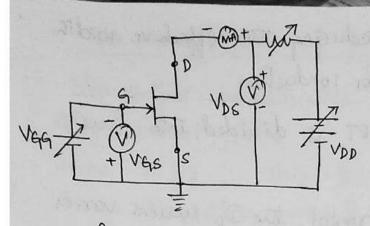
The p-channel JFET is constructed similar to the n-channel JFET but with reversal of p and n-type material as shown in figure above. Here all the current and voltage applied will be reversed.

Channel width is maximum for VGs=0. The channel width is reduced by intreaping popilize gate to source voltage. VGs is the for p-channel and VDs is regalize.

output characteristics | Drain characteristics

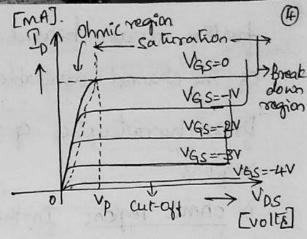
output de Drain characteristique of JFET is a plot of olp werent i.e Drain werent versus output voltage i.e Drain to source viq. Keeping viqs constant q.e input viq constant.

The experimental setup for measuring the output characteristics are as shown below.



- fig: Experimental setupts

Plot JFET characteristics



Drain characteristics.

i) when  $V_{GS} = V_{DS} = 0$ . The channel is entirely open. Its  $V_{DS} = 0$  there is no attaractive for the majority (arriver) and hence deain werent does not flow.

when VGs = 0 and when a small amount of VDS is applied. The deain when the pears to flow. As we interested to you to wounds the the voltage it interests the reverse bias on gate so race junction and the reverse bias on gate so race junction and Causes depletion region to penetrate into the Channel reducing the Channel width making the Drain current to be constant.

At some value of Vos. the dean werent ID Cannor be inversed further due to reduction in Channel width. The voltage at which ID reaches to its constant saturation level is called "pinch off" voltage (Vp).

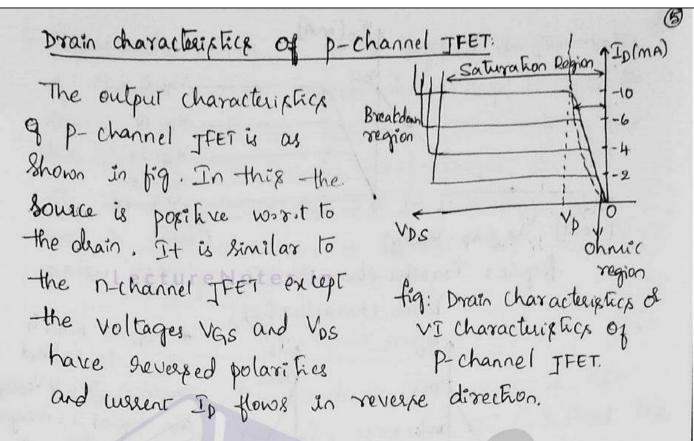
when the exteenal bias of -1 v is applied blue the gate and somece the gate channels junctions

further reverse bigsed reducing the effective width of the channel available for conduction.

Drain characteristics of JFET is divided into four regions.

- is ohmic region: In this region, the ID current varies linearly with VDS satisfying the ohmis law hence the name Ohmic region.
- Saturation region: This is the region, in which ID when semains constant and does not vary with VDS.
  - It is reduced to zero. This is laused by widening of depletion region to point where it completely closes the channel. Vas at cut-off is called Vas(off) use Notes.
  - Hy Breakdown Region: If VDS is keep on interasing, the voltage will be reached at which gate channel junction breaks down due to dvalanche effect. dt this point the deain when Inceases very rapidly and device may be destroyed.

IDSS is the maximum deain cuesent when VGS = 0. It is the saturated cuesent blue the drain & source.



Transfer characteristics of JFET

It is a plot of output werent ite In [Drain Current] to input voltage ite VGS [Gate to some vlg] keeping VDS constant.

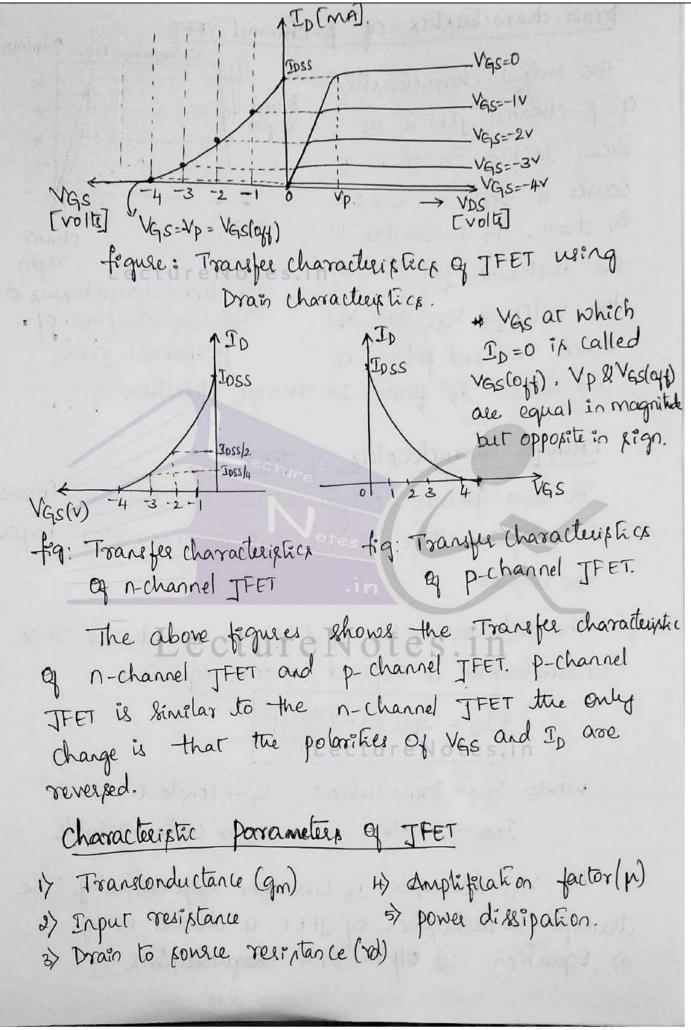
The relationship blu ID & VGs is non-linear. This characteristic is defined by the equation.

$$I_D = I_{DSS} \left[ 1 - \left( \frac{V_{GS}}{V_P} \right) \right]^2$$

where ID > Drain current Vp > Constant

IDSS > constant Vqs > control variable.

He vas decreases Is interapes exponentially. The teansfer characteristics of IFET is deaven using, if Equation of olp & Drain characteristics.



$$9m = \frac{\Delta T_D}{\Delta V_{GS}} \bigg|_{VDS = 10 \text{ Netant}}$$

mo: It is team conductance measured at VGS=0. It is normally given in the data sheet. The approximate value of gm at any point on the teamfer characteristics is calculated using.

When go is not given in the data sheet: 900 = 2 IDSS| Vaslott) |

2) Input Reniptanu: TFET operates with its gate-lource junction severe brased, which makes the input resistance at the gate very high. The input resistance can be determined by. RIN= VGS | IGSS

Igss will be given in datasher. Igss is gate reverse current. The gate reverse aurent increases with temperature

thus decreases the I/p resistance.

3) Ac deain to Source resistance (rd)

The deain resistance od is the ac resistance blue deain and source terminals when JFET is operating in saturation region. od is given by

Lect  $Volume{Tolder} = \frac{\Delta V_{DS}}{\Delta ID} |_{VGS} = constant$ 

dbove pinch eff. the drain current is relatively constant over a range of drain to source vbs. large change in Vos produces very small change in ID. Since characteristic is flat in saturation region. It may also be expressed of is not easily determined. It may also be expressed as an output admittance. The admittance is given by the expression.

Yos = I

The druphification factor is defined as rate of change of drain to source vig to rate of change of gate to source vig drain when constant

The expression for amplification factor is given by,

$$\mu = \frac{\Delta V_{DS}}{\Delta V_{GS}}$$
 ID is constant.

$$M = \frac{\Delta V_{DS}}{\Delta V_{GS}} \cdot \frac{\Delta I_{D}}{\Delta V_{GS}} = V_{d} \cdot g_{m}.$$

5) Your Dissipation: (PD)

Power dissipation can be defined as product of drain werent and drain to somece vig. The expression for power dispipation can be given by,

PD= ID. VDS

IFET Transfer characteristic is expressed by.

The above equation is also called as Square Law Or Drain wesent equation for IFET. ID can be determined for any VGs, if VGS(044) and IDSS is known. It is function of square of applied ilp voltage VGs Hence the name "Square law"

problems: Lecture Notes.11 i) For the JEET shown in fig: Vas(off) = -44 and IDSS=12mA. Determine the minimum value of VDD required to put the device in the constant current region of operation when VGS = OV

Soln: Given Ro= 560 sz. VGs(off) = -4V

: Vp = HV . IDSS = 12MA.

The minimum value of Vos for the JAET to be in Constant cullent region is | VDS = Vp = 4V

$$V_{RD} = I_D \times R_D = (12MA)(560D)$$
 $V_{RD} = 6.72V$ 

applying Kirchhof's law around the drain ext

$$V_{RD} = V_{DS} + V_{RD}$$
=  $H + 6.72$ 
 $V_{DD} = 10.72V$ 

This is the vig at VDD to make VDS=Vp and put the device in the constant when region.

2) For a 2N5459 JFET, it is given IDCS=9MA and VGs(off) = -8v (maximum). Using these values. determine the dearn werent for VGS=OV, -IV and -HV.

for 
$$V_{GS} = -IV$$
.

 $I_D = I_{DSS} \left( 1 - \frac{V_{GS}}{V_{GS}(\omega_{H})} \right)^2$ 
 $= (9MA) \left( 1 - \frac{-IV}{-8V} \right)^2$ 
 $= 9 \times 10^3 \left( 1 - 0.125 \right)^2$ 
 $I_D = 6.89 MA$ 

For 
$$V_{GS} = -4V$$

$$I_{D} = (9mA) \left(1 - \frac{-4V}{-8V}\right)^{2}$$

$$= 9 \times 10^{3} \left(1 - 0.5\right)^{2} = 9 \times 10^{3} \times 0.25$$

$$I_{D} = 2.25 mA$$
The follower gottomation is encluded

3) The following enformation is encluded in the datasher of ens457 JET. typically. IDSS = 3.0 mA, VGS(Off)=-6V maximum and qmo = 5000 µs. Using these values determine the forward transcanductance for VGs = -4V and ID at this point.

Soln: 9mo= 5000 jus, IDSS = 3×103A, VGSlayt)=-6V

$$9m = 9mo \left[1 - \frac{V_{GS}}{V_{GS}(off)}\right]$$
  
=  $5000 \left[1 - \frac{-HV}{-6V}\right]$   
 $9m = 1667\mu S$ 

$$\mathcal{I}_{D} \stackrel{\mathcal{L}}{=} \mathcal{I}_{DSS} \left[ 1 - \frac{V_{GS}}{V_{GS}(Q_{Y})} \right]^{2}$$

$$= 3 \times 10^{3} \left[ 1 - \frac{-4}{-6} \right]^{2}$$

H) A Given IFET has following characteristics: IDSS = 12 MA, VGS(041) = - 5V and gmo = 3000 ps Find

9m and ID when 
$$V_{GS} = -2V$$
.

Coln: Given:  $I_{DSS} = 12mA$ ,  $V_{GS}(off) = -5V$  and  $q_{mo} = 300qus$ 
 $V_{GS} = -2V$ .

 $V_{GS} = -2V$ .

# METAL OXIDE SEMICONDUCTOR FET [MOSFET]

This is very small hence can be used to design high density VLSI chie. Mosfers has no projunction structure, instead the gate of mosfer is insulated from Channel by a Sioz layer. Due to this 3/p resiptance is very high

Because of the insulated gate, they are also Called Of IGFET's [Insulated Gate FET's].

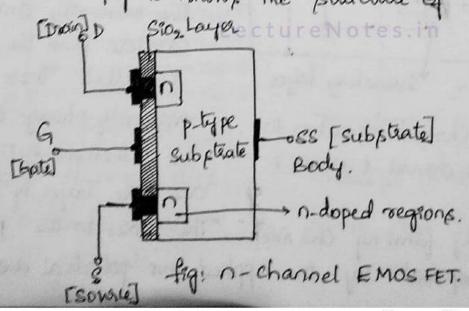
They are two types.

- 1) Depletion (0) Mosfer
- 3) Enhancement (E) MOSFET.

### Emhanument Mosfet (E-Mosfet)

E-Mosfet operates only in the enhancement mode and hop no depletion mode. There is Channel exist blue brown and the powers. we have to brate & enhance a channel blue drain and the powere hence the name Enhancement Mosfet.

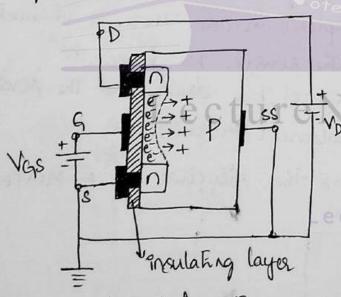
Below figure shows the structure of E-MOSFET.



Construction: Two highly doped n regions are diffused winto a leafully doped p-type substrate. The some and drain are taken our through metallic contacts to n-doped regions as shown in tig.

There is no direct contact of the gate treminal with the substeate. There is a larger of Sig which acts as a barrier of insulator blu gate treminal and the substeate. It has fore treminals. Gate, Drain and the source along with substeate (SS) treminal of body. The substeate and the source treminal is always interconnected. There is no channel exist blu Drain land the source runder no bias condition.

geration:



frg: Channel formation in N-channel E-MOSFE 7. when a tre vig VGS is applied blu the gate and the sonace terminal as shown in fig.

The tre potential at the gate treminal attracts the minority charge carriers from the p-type gub pleate. These attaracted minority charge carriers ine elections get accumulated over the layer of psubstrate.

thereby forming channel. The holes in the psubstrate gets repelled by the applied the potential and will be

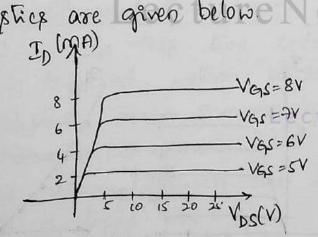
pushed down. The attaracted elections will not be able to cooks the gate terminal because of the layer of SiO2 which acts as barrier and prevents the elections in the induced channel from being attaracted by gate terminal

The vig applied blw Drain and the some ce i.e VDs attaracts the electrons which will cause the flow of Ip werent through the induced channel. As vigs inleased more electrons will be attaracted and hence inleases the Ip werent.

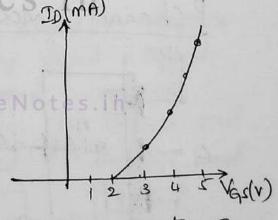
The lowest value of vgs for which there ID weent just storts flowing to called Threshold voltage (V4).

channel does not exist with VGs = 0 v and en hanced due to application of a +ve gate to somece vlg. Hence the name enhancement MOSFET.

The Drain characteristics and Transfer charactering are given below. ID(MA)



Drain characterptics



Transfer characteristics.

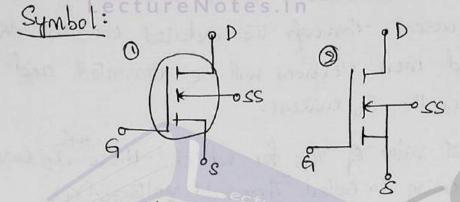
For n-channel MOSFET VGS is +ve and ID does not flow runtil VGS = VT.

For VGS VT the relationship blu drain charent and VGS is non-knear and it is given by

[ID = K (VGS-VT)<sup>2</sup>]

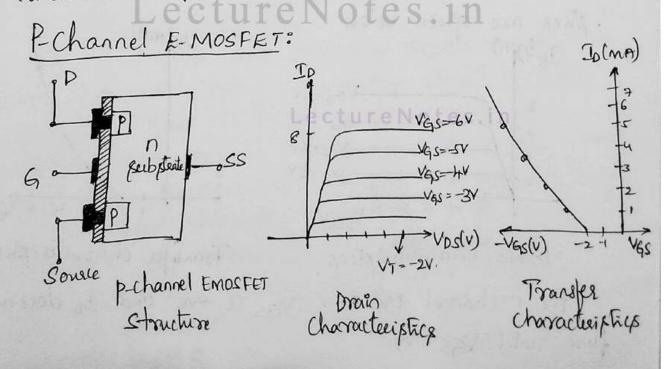
$$K = Constant$$

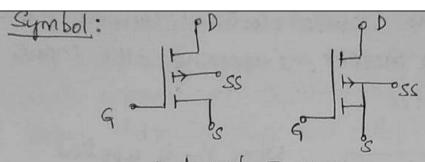
$$K = \frac{I_D(ON)}{(V_{GS}(ON) - V_f)^2}$$



n-Channel E-MOSFET.

The dotted line indicates that there is no channel blue Drain and the source. In some Cases substrate and the sources will be interconnected which is shown in figo





p-channel E-Mosfet. .

P channel E-MOSFET is exactly opposite to that of n-channel MOSFET. construction, Drain characteristics. Transfer characteristics and symbol are as shown in above fig.

[Note:] p-channel E-MOSFET and D-MOSFET construction and operation you need to study by yourself.

## Depletion MOSFET (D-MOSFET)

In this tippe of MOSFET, There exist a depletion layer or channel blue the drain and the Source under no bias condition.

n-channel D-MOSFET: Otes in

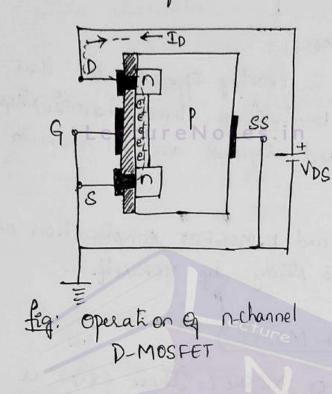
In this two specially doped n- regions are diffused within a lightly doped p-typed substrate. These enormonely doped n- regions characterises source and drain. The source and the drain terminals are linked via metallic bond to n-doped regions. So ga pob attached via n-channel.

The gate is also connected to metal surface but insulated by p-type.

A very thin layer of SiD2.

Scanned by CamScanner

Thus there is no direct electrical connection blue gateschannel of a MOSFET, increasing the input impedance of device.



when VDS is applied keeping VGS = 0 by directly connecting gate to source terminal flee elections from the n-channel are attaracted towards +ve potential & dean terminal.

This establishes werent through the channel to be denoted as IDSS at VGS=OV.

Sone ce terrinal. It regalive charges on the gate terrinal repel and get attaracted by the tre charges in the substeate. This initiates a recombination by repelled electrons and holes from the p substeate. This recombination depends on magnitude of negative voltage applied to the gate. Hence the number of free electrons reduced due to the recombination in allow or conduction reducing the Drain waren.

The n-channel is depleted some of the elections thus de usea sing the channel conductivity hence the name depletion MOSFET.

The greater the depletion of n-channel elections @ with incleasing negative bear for Vgs. the level of drain current will deduced as shown in fig. The Draw characteristics and the Transfer characteristics are as shown below. IDIMA) Depletion Norma) Johnic region. Enhanument

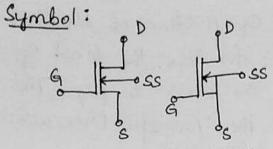
8 Ipss saturation Region. 4 IDSS/2 Ioss 4 -VGS -6VP VS VS tig: Drain characteristers fig. Transfer characteristics If the possitive voltage is applied blue the gate and source terminal. which enhances the number of electrons in the channel in conteast to that observed with Vgs = 0. Hence the segion of positive gate voltage on the teansfer characteristics can be refused as enhancement region. p-channel Depletion Type D-MOSFET The below figures shows the structure, transfer characteristics and Doarn Characteristics of p-channel In(mA) type D-MOSFET. In(mA) e Proto(0) VGS=-1V VGS=OV Substeate Substrate Gate Vos(V) Fransfer characteristics

[Sovace] structure

Scanned by CamScanner

Characteristics

Drain



N-channel DMOSFET.

p-channel D-MOSFET.

P-channel depletion type MOSFET construction is exactly reverse of n-channel deption type MOSFET. In this published is n-type, regions and channels are of p-type

Voltage polarities and current olivections are reversed. The difference from n-channel characteristics are, VDS is with negative values. VGS will have apposite polarities. and ID in the apposite direction.

# Comparision between JFET & MOSFET.

#### JFET's

1) IFET is fabricated using a semiconductor bar which acts as a channel

- 2> Fabrica hon process is complex.
- 3) IFET does not contain an insulating sikcon dioxide layer
- H) TFETS are operated in depletion made only
- of JFETS have larger drain resistance in the range of 100ks to IMs

#### MOSFET'S

is MOSFET is fabricated on a Semiconductor substrate

- 2) Fabrication process is simple and casy
- 3) MOSFET'S are fabricated with SIO2 Layer.

4) D-MOSFET is operated in both enhancement mode and depletion mode. E-MOSFET is in Enhancement mode only.

5) MOSFETS have lower drain resistances in the range of 1km to 50km.

### Basic Electronics